

Notice of References Cited	Application/Control No. 10/598,481	Applicant(s)/Patent Under Reexamination WEDOWSKI ET AL.	
	Examiner Steven H. Whitesell-Gordon	Art Unit 2882	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0144819	07-2003	Takeuchi et al.	702/189
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Malinowski et al., "Controlling contamination in Mo/Si multilayer mirrors by Si surface-capping modifications", SPIE Symposium on Emerging Lithographic Technologies Vi, 2002, Vol. 4688, p. 442
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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